

Appl. No. (not yet known)

Preliminary Amendment filed 23 December 2004

Title: SPECIMEN HOLDER FOR AN ELECTRON MICROSCOPE, AND
METHOD FOR REDUCING THERMAL DRIFT IN A MICROSCOPE

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims

1 Claim 1 (original): A specimen holder for an electron
2 microscope, comprising a rod-shaped part (2), which is
3 provided near one end with a tip (3), which tip (3) is
4 arranged to receive a specimen, the rod-shaped part (2), in
5 use, extending with at least the tip (3) into the electron
6 microscope, held by clamping means (5) present in the
7 electron microscope, wherein first temperature control
8 means (10) are provided to control the temperature of the
9 rod-shaped part (2) and/or the clamping means (5), such that
10 this rod-shaped part (2) and the clamping means (5)
11 substantially have the same temperature, at least at the
12 location of their contact surfaces.

1 Claim 2 (original): A specimen holder according to claim 1,
2 wherein the first temperature control means (10) comprise a
3 cooling element and/or a heating element.

1 Claim 3 (currently amended): A specimen holder according to
2 | claim 1—or 2, wherein second temperature control means are
3 | provided to control the temperature of the tip (3), at least
4 | a part of the tip (3) arranged to receive the specimen, the
5 | second temperature control means comprising cooling means
6 | and/or heating means.

1 Claim 4 (currently amended): A specimen holder according to
2 any one of the preceding claims claim 1, wherein the first
3 temperature control means (10) are provided around at least
4 a part of the rod-shaped part (2).

1 Claim 5 (original): A specimen holder according to claim 4,
2 wherein at least a part of the first temperature control
3 means (10) is arranged near the tip (3) of the specimen
4 holder (1).

1 Claim 6 (currently amended): A specimen holder according to
2 any one of the preceding claims claim 1, wherein the rod-
3 shaped part (2), in use, is held in at least two spaced
4 apart positions by the clamping means (5), the first
5 temperature control means (10) being arranged to keep the
6 rod-shaped part (2), at least the outer surface thereof,
7 between the holding positions at the same temperature as the
8 temperature of the clamping means (5).

1 Claim 7 (currently amended): A specimen holder, in
2 particular according to any one of the preceding
3 claims claim 1, wherein between the tip (3) and the outer
4 surface of the rod-shaped part (2) a substantially shell-
5 shaped connecting element (8) is provided, manufactured from
6 a relatively stiff, impact resistant, thermally insulating
7 material, openings (9) being provided in the shell.

1 Claim 8 (original): A specimen holder according to claim 7,
2 wherein the openings (9) of the shell-shaped connecting
3 element (8) are such that the heat conduction is at least
4 less than one tenth of a comparable structure without
5 openings, preferably less than one hundredth.

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1 Claim 9 (currently amended): A specimen holder according to
2 | claim 7-~~or~~-8, wherein the shell-shaped connecting
3 | element (8) is manufactured from titanium.

1 Claim 10 (currently amended): A specimen holder according to
2 | ~~any one of the preceding claims~~claim 1, in which the first
3 | and/or the second temperature control means comprise a
4 | temperature sensor.

1 Claim 11 (original): A specimen holder according to
2 | claim 10, wherein the temperature sensor comprises a thermo
3 | couple (11).

1 Claim 12 (currently amended): A specimen holder according to
2 | ~~any one of the preceding claims~~claim 1, wherein the tip (3)
3 | comprises a frame (20) and a platform (24), provided with a
4 | recess (25) to receive the specimen, which platform (24) is
5 | suspended by means of a subframe (22) so as to be tilttable
6 | in the frame (20), which frame (20) and subframe (22) are
7 | manufactured from two different materials having a different
8 | expansion coefficient and are dimensioned and positioned
9 | relative to each other such that expansion or shrinkage of
10 | the frame and the subframe outweigh each other as a result
11 | of temperature changes occurring in the tip (3) during use,
12 | such that a specimen placed on the platform (24) during use
13 | is substantially not displaced.

1 Claim 13 (original): A specimen holder according to
2 | claim 12, wherein the frame (20) is manufactured from
3 | tungsten and the subframe (22) from aluminum.

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1 Claim 14 (currently amended): A specimen holder according to
2 | ~~any one of the preceding claims~~ claim 1, wherein the
3 | rod-shaped part (2) is manufactured from a material which
4 | has a relatively good heat conduction and a relatively low
5 | thermal expansion coefficient and is preferably not
6 | magnetic.

1 Claim 15 (original): An assembly of an electron microscope
2 and a specimen holder (1), wherein the electron microscope
3 is provided with clamping means (5) for holding the specimen
4 holder (1) in the electron microscope, which electron
5 microscope comprises third temperature control means to keep
6 the clamping means (5) at a desired temperature and the
7 specimen holder (1) comprises first temperature control
8 means (10) to keep at least a part of the specimen
9 holder (1) being in contact with these clamping means (5)
10 substantially at the same temperature as the clamping
11 means (5).

1 Claim 16 (currently amended): A method for reducing thermal
2 drift in an electron microscope, comprising the following
3 steps:

4 | _____ placing a specimen on the specimen holder (1);
5 | _____ fixing the specimen holder (1) in the electron
6 | microscope in clamping means (5) suitably provided in the
7 | electron microscope;
8 | _____ adapting the temperature of the specimen
9 | holder (1) and/or the clamping means (5), so that both
10 | obtain and keep substantially the same temperature.